

Date Searched: 5/13/2003

Databases Searched: USPAT, USPGPUB

Plurals: ON

Terms Searched:

L1 716/\$.ccls.

L2 ((function or functionally or functionality or logic or logical or logically) near3 (equal or equivalen\$2 or "same" or similar or identical or identically or identity)

L3 threshold same (shape or size or area) same delay same power

L4 1 and 2 and 3

Results: 7 hits

L5 (shape or size or area) near3 (equal or equivalen\$2 or "same" or similar or identical or identically or identity)

L6 1 and 2 and 5

Results: 431 hits

L7 (delay or timing or time) same different\$2 same power

L8 6 and 7

Results: 58 hits

L9 (shape or pattern) near5 (equal or equivalen\$2 or "same" or similar or identical or identically or identity)

L11 (threshold or thresh-hold or tolerance or threshold or level) near5 voltage

L12 1 and 2 and 9 and 11

Results: 37 hits

L13 (threshold or thresh-hold or tolerance or threshold or ((critical or predetermined or pre-determined) adj (value or level))) same (delay or skew or slack) same transistor

L14 1 and 13

Results: 45 hits

L15 (path or route or routing or datapath)

L16 14 and 16

Results: 37 hits

L17 insert\$4 same (delay or time or timing or skew or slack) same (path or datapath) same threshold

Results: 200 hits

L18 insert\$4 same (delay or time or timing or skew or slack) same (path or datapath) same transistor

L19 1 and 18

Results: 11 hits

US 5898742 A USPAT Van Der Werf, Albert 375/354

US 6209122 B1 USPAT Jyu, Henry Horng-Fei et al. 716/6

US 5880967 A USPAT Jyu, Henry Horng-Fei et al. 716/6

US 6272668 B1 USPAT Teene, Andres R. 716/10

US 6035106 A USPAT Carruthers, Colin et al. 703/1

US 5872716 A USPAT Yano, Kazuo et al. 716/1

US 6009248 A USPAT Sato, Koichi et al. 716/2

US 5774367 A USPAT Reyes, Alberto J. et al. 716/2

US 6167554 A USPAT Ishikawa, Takashi et al. 716/1

US 5983007 A USPAT Agrawal, Vishwani Deo 716/6

US 6038381 A USPAT Munch, Michael et al. 716/1

US 5654898 A USPAT Roetcisoender, Bradley R. et al. 716/9

US 6209123 B1 USPAT Maziasz, Robert L. et al. 716/14

US 6006024 A USPAT Guruswamy, Mohankumar et al. 716/12

US 5984510 A USPAT Guruswamy, Mohan et al. 716/2

US 5822214 A	USPAT Rostoker, Michael D. et al.	716/10
US 4839820 A	USPAT Kinoshita, Tsuneo et al.	716/12
US 4656592 A	USPAT Spaanenburg, Lambertus et al.	716/7
US 5831864 A	USPAT Raghunathan, Anand et al.	716/2
US 5636130 A	USPAT Salem, Raoul B. et al.	716/6

Databases Searched: EPO, JPO, IBM TDB, Derwent

Plurals: ON

Terms Searched:

L1 ((shape or pattern) near5 (equal or equivalen\$2 or "same" or similar or identical or identically or identity)) and ((threshold or thresh-hold or tolerance or threshold or level) near5 voltage) and ((function or functionally or functionality or logic or logical or logically) near5 (equal or equivalen\$2 or "same" or similar or identical or identically or identity))

Results: 7 hits

L2 ((threshold or thresh-hold or tolerance or threshold or ((critical or predetermined or pre-determined) adj (value or level))) same (delay or skew or slack) same transistor)

Results: 777 hits

L3 2 and g06f017/\$.ipc.

Results: 11 hits

L4 (IBM TDB only) 2

Results: 212 hits

L5 (((threshold or thresh-hold or tolerance or threshold or ((critical or predetermined or pre-determined) adj (value or level))) same (delay or skew or slack) same transistor)) and ((path or route or routing or datapath))

Results: 100 hits

L6 5 and g06f017/\$.ipc.

Results: 6 hits

L7 (IBM TDB only) 5

Results: 43 hits

JP 09205148 A	JPO WAKABAYASHI, SHIGEMICHI et al.
JP 09319775 A	DERWENT
NB9001420	IBM_TDB
NA84035023	IBM_TDB
NN87044929	IBM_TDB

Database Searched: IEE/IEEE Xplore

Terms Searched: ((shape or pattern) <near/5> (equal or equivalen* or same or similar or identical or identically or identity)) and ((threshold or thresh-hold or tolerance or threshold or level) <near/5> voltage) and ((function or functionally or functionality or logic or logical or logically) <near/5> (equal or equivalen* or "same" or similar or identical or identically or identity))

Results: Your search matched [0] of [939702] documents.

Terms Searched: (threshold or thresh-hold or tolerance or threshold or ((critical or predetermined or pre-determined) <near/1> (value or level))) and (delay or skew or slack) and transistor

Results: Your search matched 156 of 939702 documents.

Terms Searched: thresh-hold or tolerance or threshold or ((critical or predetermined or pre-determined) <near/1> (value or level))) and (delay or skew or slack)

Results: Your search matched 58 of 939702 documents.